

Micro Power 3 V Linear Hall Effect Sensor ICs withTri-State Output and User-Selectable Sleep Mode

Features and Benefits

- High-impedance output during sleep mode
- Compatible with 2.5 to 3.5 V power supplies
- 10 mW power consumption in the active mode
- Miniature MLP/DFN package
- Ratiometric output scales with the ratiometric supply reference voltage (VREF pin)
- Temperature-stable quiescent output voltage and sensitivity
- Wide ambient temperature range: -20°C to 85°C
- ESD protection greater than 3 kV
- Solid-state reliability
- Preset sensitivity and offset at final test

Package: 6 pin MLP/DFN (suffix EH)



Description

The A139x family of linear Hall effect sensor integrated circuits (ICs) provide a voltage output that is directly proportional to an applied magnetic field. Before amplification, the sensitivity of typical Hall effect ICs (measured in mV/G) is directly proportional to the current flowing through the Hall effect transducer element inside the ICs. In many applications, it is difficult to achieve sufficient sensitivity levels with a Hall effect sensor IC without consuming more than 3 mA of current. The A139x minimize current consumption to less than 25 µA through the addition of a user-selectable sleep mode. This makes these devices perfect for battery-operated applications such as: cellular phones, digital cameras, and portable tools. End users can control the current consumption of the A139x by applying a logic level signal to the SLEEP pin. The outputs of the devices are not valid (high-impedance mode) during sleep mode. The high-impedance output feature allows the connection of multiple A139x Hall effect devices to a single A-to-D converter input.

The quiescent output voltage of these devices is 50% nominal of the ratiometric supply reference voltage applied to the VREF pin of the device. The output voltage of the device is not ratiometric with respect to the SUPPLY pin.

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Functional Block Diagram

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Description (continued)

Despite the low power consumption of the circuitry in the A139x, the features required to produce a highly-accurate linear Hall effect IC have not been compromised. Each BiCMOS monolithic circuit integrates a Hall element, improved temperature-compensating circuitry to reduce the intrinsic sensitivity drift of the Hall element, a small-signal high-gain amplifier, and proprietary dynamic

offset cancellation circuits. End of line, post-packaging, factory programming allows precise control of device sensitivity and offset.

These devices are available in a small 2.0×3.0 mm, 0.75 mm nominal height microleaded package (MLP/DFN). It is Pb (lead) free, with 100% matte tin leadframe plating.

Selection Guide

Part Number	Sensitivity (mV/G, Typ.)	Package	Packing ¹
A1391SEHLT-T ²	1.25	DFN/MLP 2x3 mm; 0.75 mm nominal height	7-in. reel, 3000 pieces/reel
A1392SEHLT-T ²	2.50	DFN/MLP 2×3 mm; 0.75 mm nominal height	7-in. reel, 3000 pieces/reel
A1393SEHLT-T ²	5	DFN/MLP 2×3 mm; 0.75 mm nominal height	7-in. reel, 3000 pieces/reel
A1395SEHLT-T ²	10	DFN/MLP 2×3 mm; 0.75 mm nominal height	7-in. reel, 3000 pieces/reel



¹Contact Allegro[™] for additional packing options.

²Allegro products sold in DFN package types are not intended for automotive applications.

Absolute Maximum Ratings*

Characteristic	Symbol	Notes	Rating	Unit
Supply Voltage	V _{CC}		8	V
Reverse-Supply Voltage	V _{RCC}		-0.1	V
Ratiometric Supply Reference Voltage	V _{REF}		7	V
Reverse-Ratiometric Supply Reference Voltage	V _{RREF}		-0.1	V
Logic Supply Voltage	V _{SLEEP}	(V _{CC} > 2.5 V)	32	V
Reverse-Logic Supply Voltage	VRSLEEP		-0.1	V
Output Voltage	V _{OUT}		V _{CC} + 0.1	V
Reverse-Output Voltage	V _{ROUT}		-0.1	V
Operating Ambient Temperature	T _A	RangeS	-20 to 85	°C
Junction Temperature	T _J (MAX)		165	°C
StorageTemperature	T _{stg}		-65 to 170	°C

*All ratings with reference to ground

Pin-out Diagram



Terminal List Table

Pin	Name	Function
1	VCC	Supply
2	OUT	Output
3	GND	Ground
4	GND	Ground
5	SLEEP	Toggle sleep mode
6	VREF	Supply for ratiometric reference



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Device Characteristics Tables

Characteristic	Symbol	Test Conditions	Min.	Typ. ¹	Max.	Units
Supply Voltage	V _{CC}		2.5	_	3.5	V
Nominal Supply Voltage	V _{CCN}		-	3.0	_	V
Supply Zener Clamp Voltage	V _{CCZ}	I _{CC} = 7 mA, T _A = 25°C	6	8.3	_	V
Ratiometric Reference Voltage ²	V _{REF}		2.5	-	V _{CC}	V
Ratiometric Reference Zener Clamp Voltage	V _{REFZ}	I_{VREF} = 3 mA, T_A = 25°C	6	8.3	-	V
SLEEP Input Voltage			-0.1	_	V _{CC} + 0.5	V
SLEEP Input Threshold	V _{INH}	For active mode	-	0.45 × V _{CC}	_	V
SLEEP Input Inteshold	V _{INL}	For sleep mode	- 1	0.20 × V _{CC}	_	V
	R _{REF}	$V_{SLEEP} > V_{INH}$, $V_{CC} = V_{CCN}$, $T_A = 25^{\circ}C$	250	_	-	kΩ
Ratiometric Reference Input Resistance		$V_{SLEEP} < V_{INL,} V_{CC} = V_{CCN,}$ $T_A = 25^{\circ}C$	_	5	-	MΩ
Chopper Stabilization Chopping Frequency	f _C	$V_{CC} = V_{CCN}, T_A = 25^{\circ}C$	-	200	-	kHz
SLEEP Input Current	I _{SLEEP}	V_{SLEEP} = 3 V, V_{CC} = V_{CCN}	-	1	-	μΑ
Supply Current ³	I _{CC}	$V_{SLEEP} < V_{INL,} V_{CC} = V_{CCN,}$ $T_A = 25^{\circ}C$	-	0.025	-	mA
		$V_{SLEEP} > V_{INH}$, $V_{CC} = V_{CCN,}$ $T_A = 25^{\circ}C$	-	3.2	-	mA
Quiescent Output Power Supply Rejection ⁴	PSR _{VOQ}	f _{AC} < 1 kHz	-	-60	-	dB

ELECTRICAL CHARACTERISTICS valid through full operating ambient temperature range, unless otherwise noted

¹Typical data are for initial design estimations only, and assume optimum manufacturing and application conditions, such as $T_A = 25^{\circ}$ C. Performance may vary for individual units, within the specified maximum and minimum limits.

 2 Voltage applied to the VREF pin. Note that the V_{REF} voltage must be less than or equal to V_{cc}. Degradation in device accuracy will occur with applied voltages of less than 2.5 V.

 3 If the VREF pin is tied to the VCC pin, the supply current would be I_{CC} + V_REF / R_REF

 4 $\rm f_{AC}$ is any AC component frequency that exists on the supply line.



Micro Power 3 V Linear Hall Effect Sensor ICs with Tri-State Output and User Selectable Sleep Mode

OUTPUT CHARACTERISTICS valid through full operating ambient temperature range, unless otherwise noted

Characteristic	Symbol		Test Conditions	Min.	Typ.1	Max.	Units
Linear Output Voltage	V _{OUTH}	V _{CC} = V	$V_{\rm CCN}, V_{\rm REF} \le V_{\rm CC}$	_	V _{REF} – 0.1	-	V
Range	V _{OUTL}	$V_{CC} = V$	$V_{\rm CCN}, V_{\rm REF} \le V_{\rm CC}$	_	0.1	-	V
Maximum Voltage Applied to Output	V _{OUTMAX}	V _{SLEEP}	< V _{INL}	_	-	V _{CC} + 0.1	V
		A1391	$T_A = 25^{\circ}C, V_{CC} = V_{REF} = V_{CCN}$	-	1.25	-	mV/G
Sensitivity ²	Sens	A1392	$T_A = 25^{\circ}C, V_{CC} = V_{REF} = V_{CCN}$	-	2.50	-	mV/G
Sensitivity-	Selis	A1393	$T_A = 25^{\circ}C, V_{CC} = V_{REF} = V_{CCN}$	-	5	-	mV/G
		A1395	$T_A = 25^{\circ}C, V_{CC} = V_{REF} = V_{CCN}$	-	10	-	mV/G
Quiescent Output	V _{OUTQ}	$T_{A} = 25$	5°C, B = 0 G	-	0.500 × V _{REF}	-	V
Output Resistance ³	R _{OUT}	$f_{out} = 1$	kHz, $V_{SLEEP} > V_{INH}$, active mode	-	20	-	Ω
		$f_{out} = 1$	kHz, $V_{SLEEP} < V_{INL}$, sleep mode	-	4M	-	Ω
Output Load Resistance	RL	Output	to ground	15	-	-	kΩ
Output Load Capacitance	CL	Output	to ground	-	-	10	nF
Output Bandwidth	BW	-3 dB V _{CC} = V	-3 dB point, V_{OUT} = 1 V_{pp} sinusoidal, $V_{CC} = V_{CCN}$		10	_	kHz
		1391	C _{bypass} = 0.1 μF, BW _{externalLPF} = 2 kHz	_	6	12	mV _{pp}
			$C_{bypass} = 0.1 \ \mu F$, no load	_	-	20	mV _{pp}
Noise ^{4,5}	V _n	1392	$C_{bypass} = 0.1 \ \mu F$, no load	_	-	40	mV _{pp}
		1393	C _{bypass} = 0.1 μF, BW _{externalLPF} = 2 kHz	_	12	24	mV _{pp}
			$C_{bypass} = 0.1 \ \mu F$, no load	-	-	40	mV _{pp}
		1395	$C_{bypass} = 0.1 \ \mu F$, no load	_	-	80	mV _{pp}

¹Typical data are for initial design estimations only, and assume optimum manufacturing and application conditions, such as $T_A = 25^{\circ}C$. Performance may vary for individual units, within the specified maximum and minimum limits.

²For V_{REF} values other than V_{REF} = V_{CCN}, the sensitivity can be derived from the following equation: $K \times V_{REF}$, where K =0.416 for the A1391, K= 0.823 for the A1392, K = 1.664 for the A1393, and K = 3.328 for the A1395.

 $^3f_{\rm OUT}$ is the output signal frequency_

⁴Noise specification includes digital and analog noise.

⁵Values for BW_{externalLPF} do not include any noise resulting from noise on the externally-supplied VREF voltage.



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OUTPUT TIMING CHARACTERISTICS¹ $T_A = 25^{\circ}C$

Characteristic	Symbol	Test Conditions	Min.	Typ. ²	Max.	Units
Power-On Time ³	t _{PON}		-	40	60	μs
Power-Off Time ⁴	t _{POFF}		—	1	_	μs

¹See figure 1 for explicit timing delays.

²Typical data are for initial design estimations only, and assume optimum manufacturing and application conditions, such as $T_A = 25^{\circ}$ C. Performance may vary for individual units, within the specified maximum and minimum limits.

³Power-On Time is the elapsed time after the voltage on the SLEEP pin exceeds the active mode threshold voltage, V_{INH}, until the time the device output reaches 90% of its value.

⁴Power-Off Time is the duration of time between when the signal on the \overline{SLEEP} pin switches from HIGH to LOW and when I_{CC} drops to under 100 µA. During this time period, the output goes into the HIGH impedance state.

MAGNETIC CHARACTERISTICS $T_A = 25^{\circ}C$

Characteristic	Symbol	Test Conditions	Min.	Тур.*	Max.	Units
Ratiometry	ΔV _{OUTQ(ΔV)}		-	100	-	%
Ratiometry	ΔSens _(ΔV)		-	100	-	%
Positive Linearity	Lin+		-	100	-	%
Negative Linearity	Lin–		-	100	-	%
Symmetry	Sym		-	100	-	%

*Typical data are for initial design estimations only, and assume optimum manufacturing and application conditions, such as T_A = 25°C. Performance may vary for individual units, within the specified maximum and minimum limits.

